

# GSMDD10N20

## 200V N-Channel MOSFETs

### Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

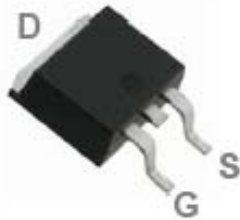
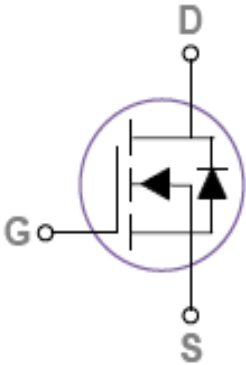
### Features

- 200V, 8A,  $R_{DS(ON)}=400m\Omega@V_{GS}=10V$
- Improved dv/dt capability
- Fast switching
- $V_{GS}$  Guaranteed  $\pm 25V$
- Green Device Available
- TO-252-2L package design

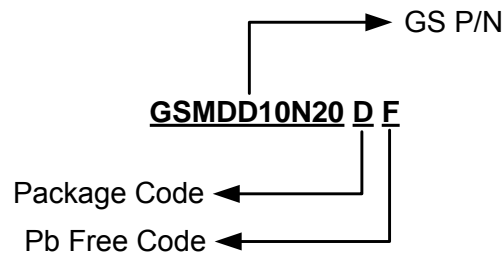
### Applications

- Notebook
- Load Switch
- LED Applications
- Li Battery Pack Application

### Packages & Pin Assignments

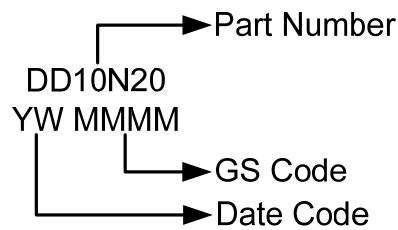
GSMDD10N20DF (TO-252-2L)	
 <p>Top View</p>	
<b>Description</b>	
Gate	
Source	
Drain	

## Ordering Information



Part Number	Package	Quantity Reel
GSMDD10N20DF	TO-252-2L	2500 PCS

## Marking Information



## Absolute Maximum Ratings

$T_A=25^{\circ}\text{C}$  Unless otherwise noted

Symbol	Parameter	Typical	Unit
$V_{DS}$	Drain-Source Voltage	200	V
$V_{GS}$	Gate-Source Voltage	$\pm 25$	V
$I_D$	Continuous Drain Current	$T_A=25^{\circ}\text{C}$	8
		$T_A=100^{\circ}\text{C}$	5
$I_{DM}$	Pulsed Drain Current	32	A
$P_D$	Power Dissipation ( $T_A=25^{\circ}\text{C}$ )	50	W
	Power Dissipation (Derate above $25^{\circ}\text{C}$ )	0.4	W/ $^{\circ}\text{C}$
$T_J$	Operating Junction Temperature Range	-55 to +150	$^{\circ}\text{C}$
$T_{STG}$	Storage Temperature Range	-55 to +150	$^{\circ}\text{C}$
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	62	$^{\circ}\text{C}/\text{W}$
$R_{\theta JC}$	Thermal Resistance-Junction to Case	2.5	$^{\circ}\text{C}/\text{W}$

Note 1: Repetitive Rating : Pulsed width limited by maximum junction temperature.

## Electrical Characteristics

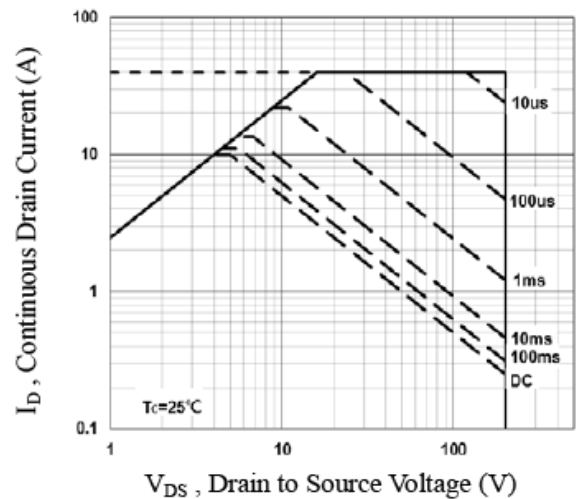
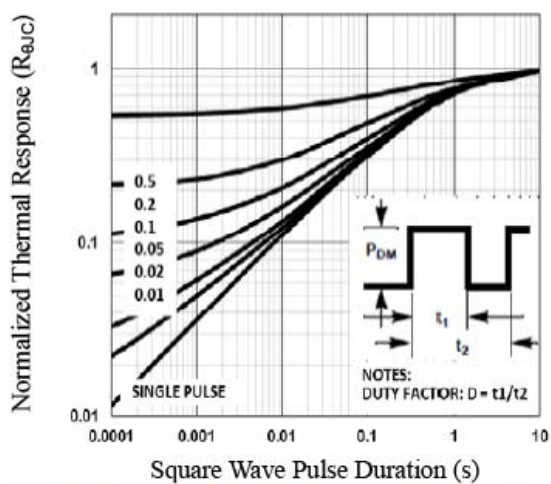
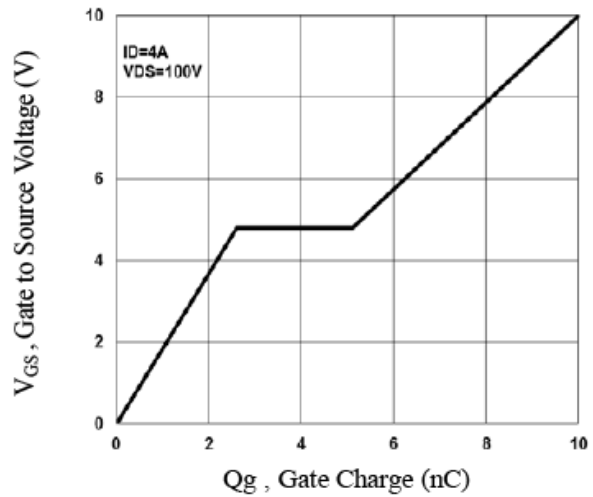
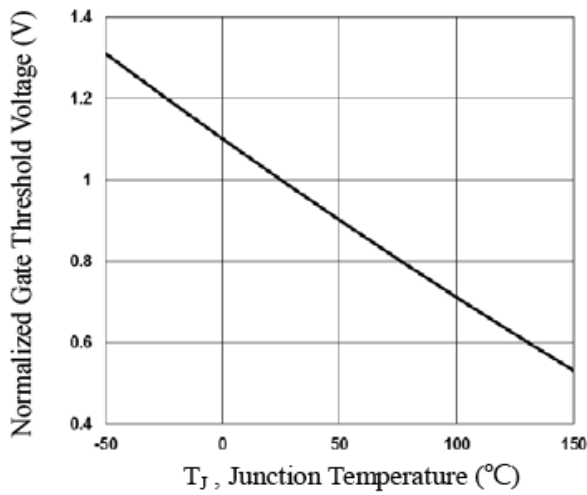
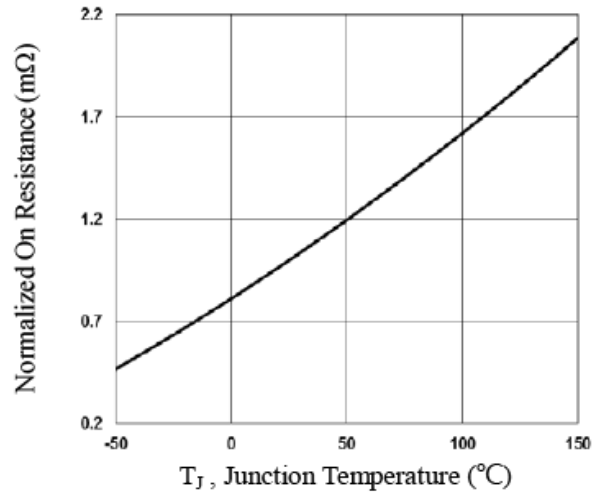
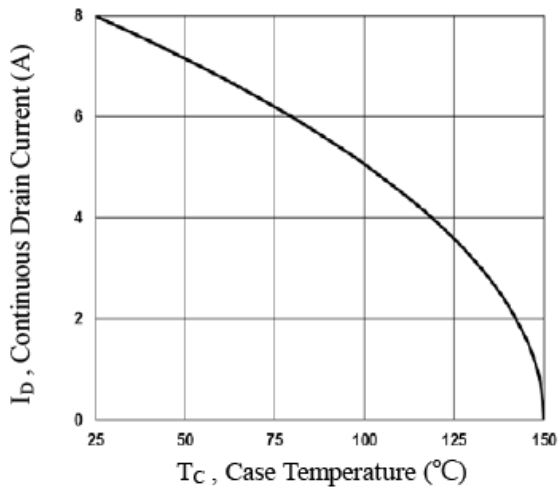
T<sub>A</sub>=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	200			V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA		0.08		V/°C
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	2	3	4	V
ΔV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient			-6		mV/°C
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±25V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =160V, V <sub>GS</sub> =0V			1	uA
		V <sub>DS</sub> =160V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			30	
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			8	A
I <sub>SM</sub>	Pulsed Source Current				32	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =4A		320	400	mΩ
V <sub>SD</sub>	Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =1A			1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> =0V, I <sub>S</sub> =1A, di/dt=100A/us		67		ns
Q <sub>rr</sub>	Reverse Recovery Charge			114		nC
<b>Dynamic</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =100V, V <sub>GS</sub> =10V, I <sub>D</sub> =4A		10	15	nC
Q <sub>gs</sub>	Gate-Source Charge			2.6	4	
Q <sub>gd</sub>	Gate-Drain Charge			2.5	5	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V, f=1MHz		500	730	pF
C <sub>oss</sub>	Output Capacitance			41	60	
C <sub>rss</sub>	Reverse Transfer Capacitance			16	30	
t <sub>d(on)</sub>	Turn-On Time	V <sub>DD</sub> =30V, I <sub>D</sub> =1A, V <sub>GS</sub> =10V, R <sub>G</sub> =6Ω		9	16	ns
t <sub>r</sub>				8	15	
t <sub>d(off)</sub>	Turn-Off Time			18	33	
t <sub>f</sub>				3	6	
R <sub>g</sub>	Gate Resistance		V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz		3	

Note 2: The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.

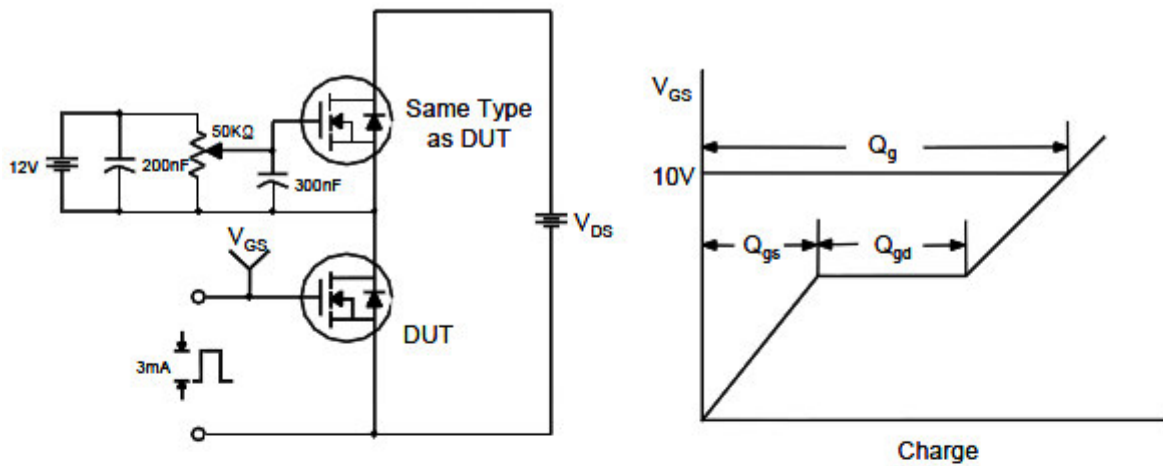
Note 3: Essentially independent of operating temperature.

## Typical Performance Characteristics



## Typical Performance Characteristics (Continue)

### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms

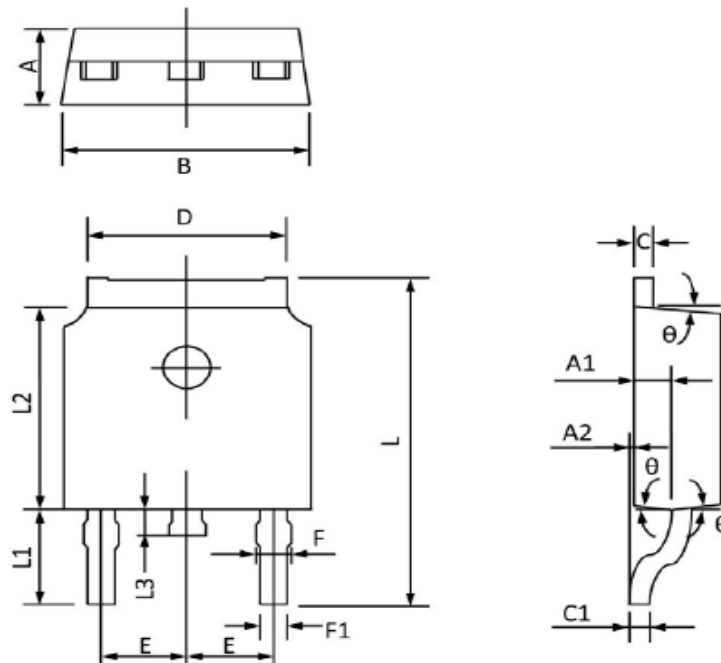


### Unclamped Inductive Switching Test Circuit & Waveforms



## Package Dimension

### TO-252-2L










Dimensions				
Symbol	Millimeters		Inches	
	Min	Max	Min	Max
A	2.20	2.40	0.087	0.094
A1	0.91	1.11	0.036	0.044
A2	0.00	0.15	0.000	0.006
B	6.40	6.80	0.252	0.268
C	0.46	0.58	0.018	0.023
C1	0.46	0.58	0.018	0.023
D	5.10	5.50	0.201	0.217
E	2.186	2.386	0.086	0.094
F	0.60	0.94	0.024	0.037
F1	0.50	0.86	0.020	0.034
L	9.40	10.40	0.370	0.409
L1	2.40	3.00	0.094	0.118
L2	5.40	6.20	0.213	0.244
L3	0.60	1.20	0.024	0.047
$\theta$	3°	9°	3°	9°



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